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FIG. 1

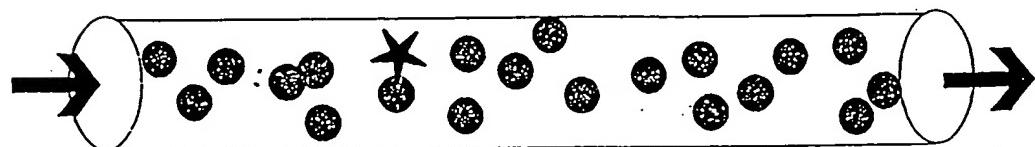
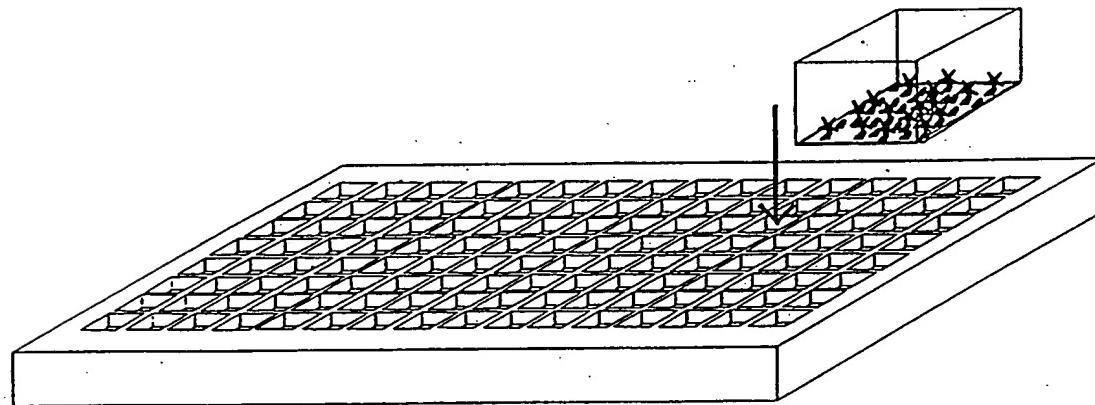
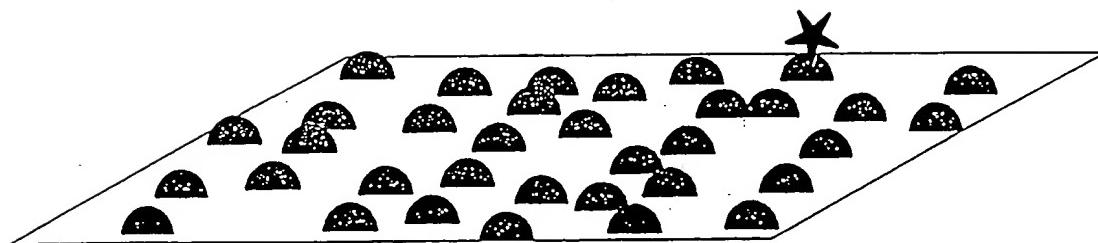


FIG. 2

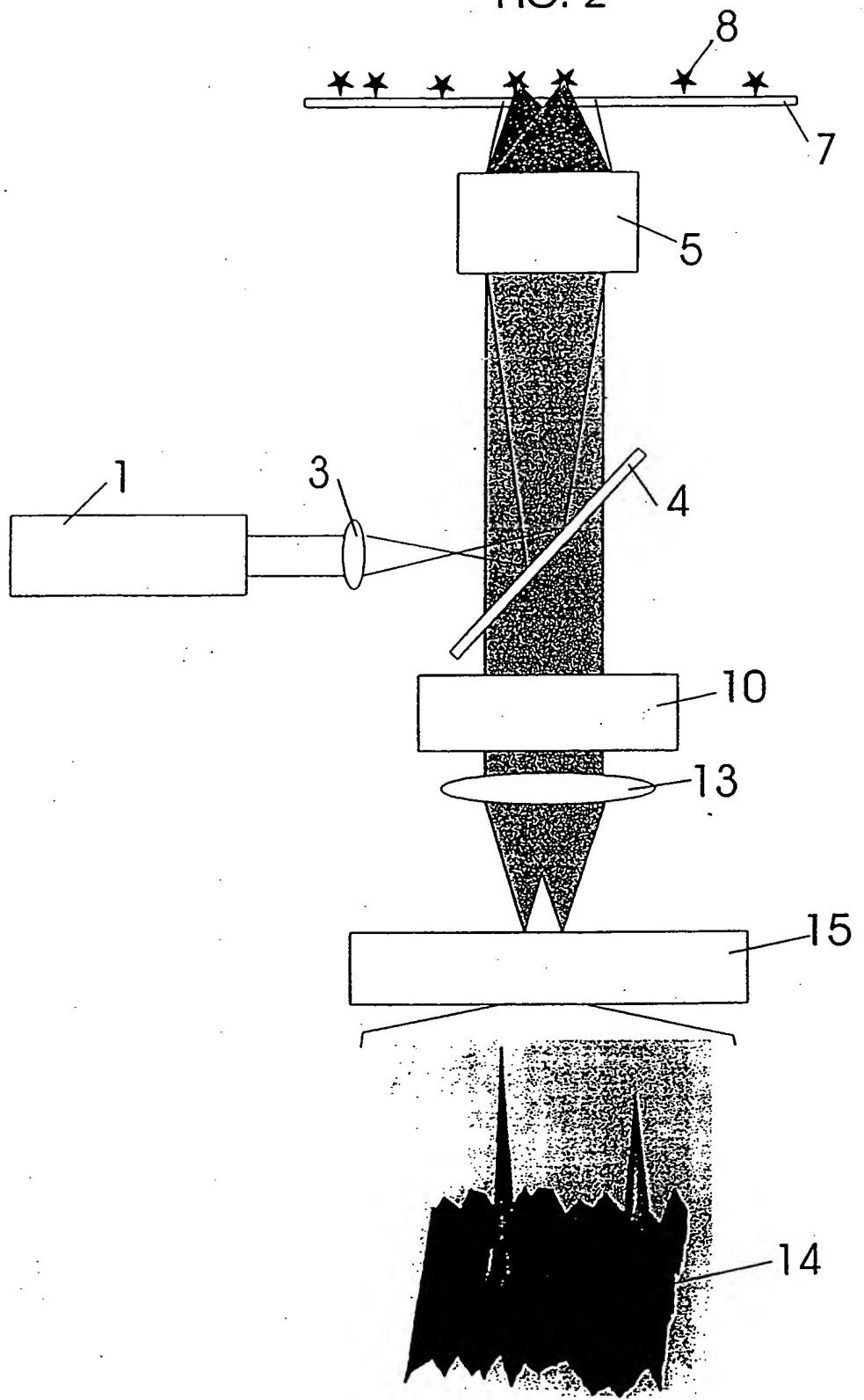


FIG. 3

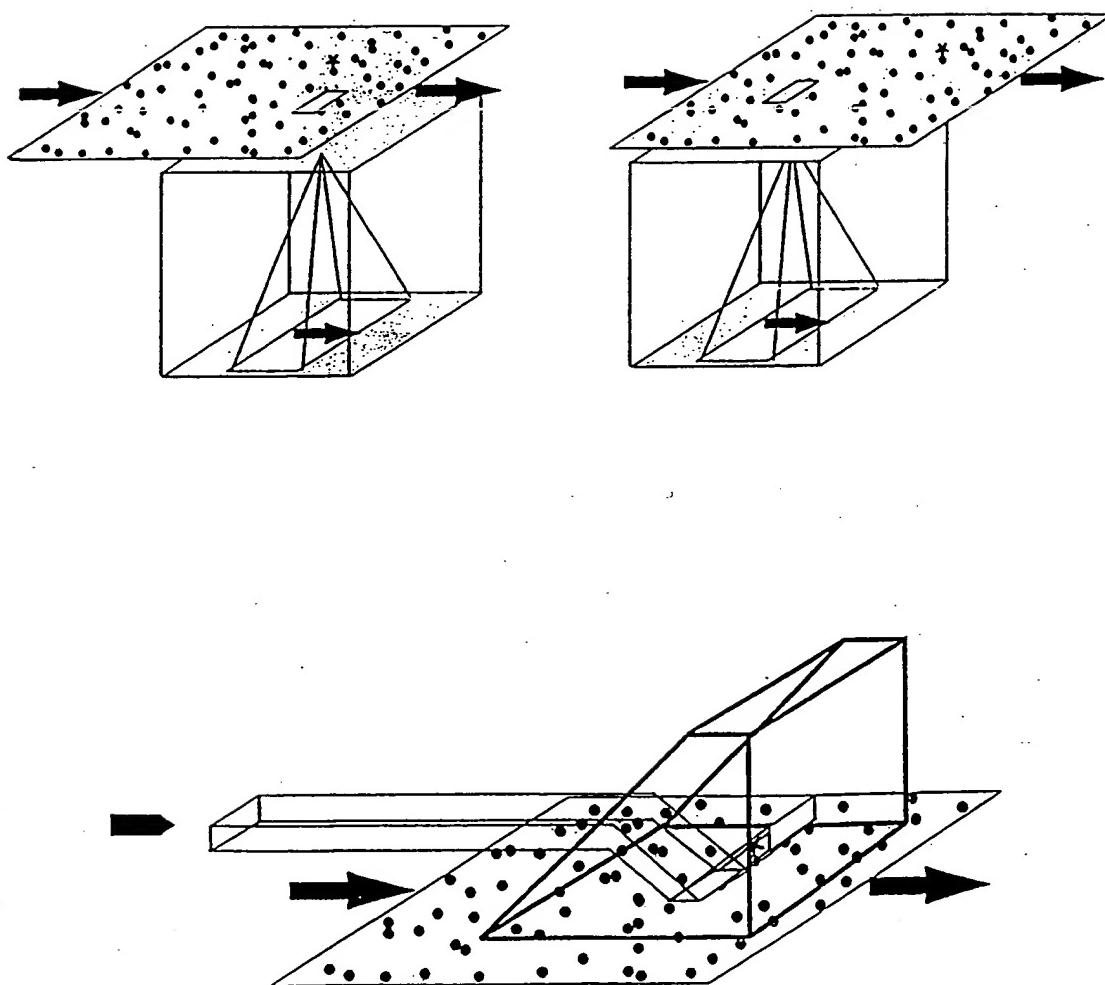


FIG. 4

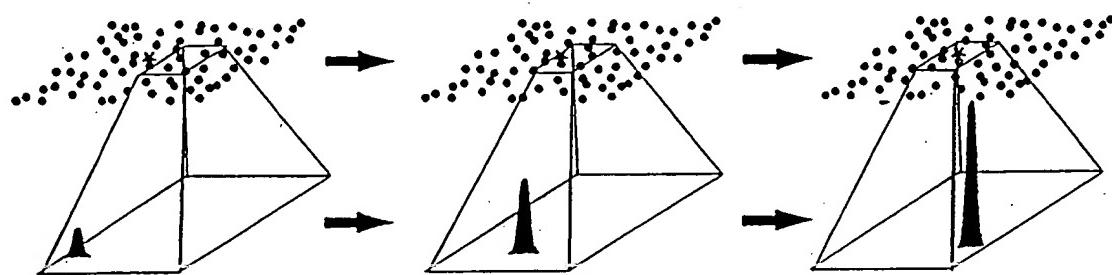


FIG. 5

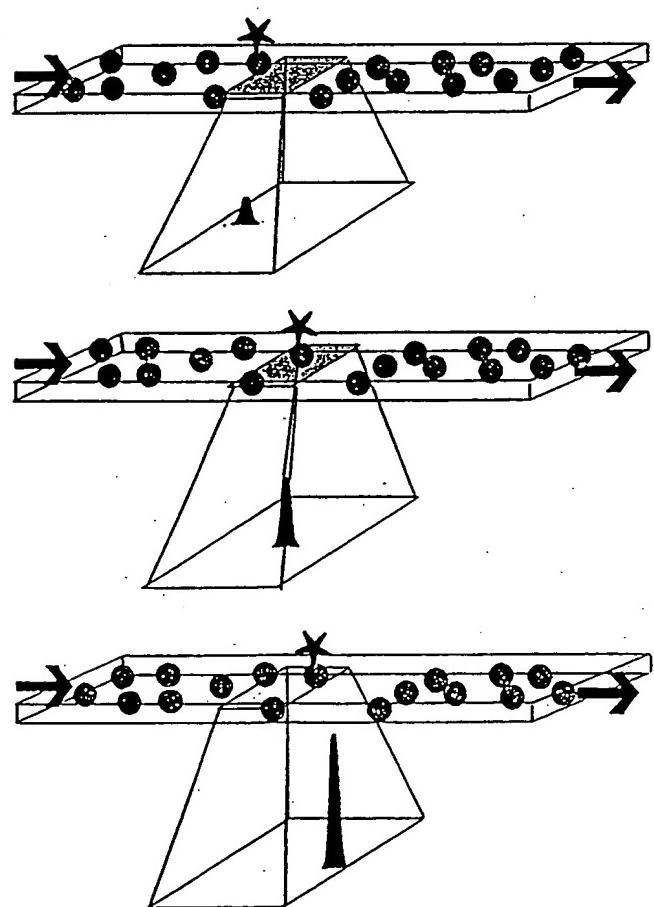


FIG. 6

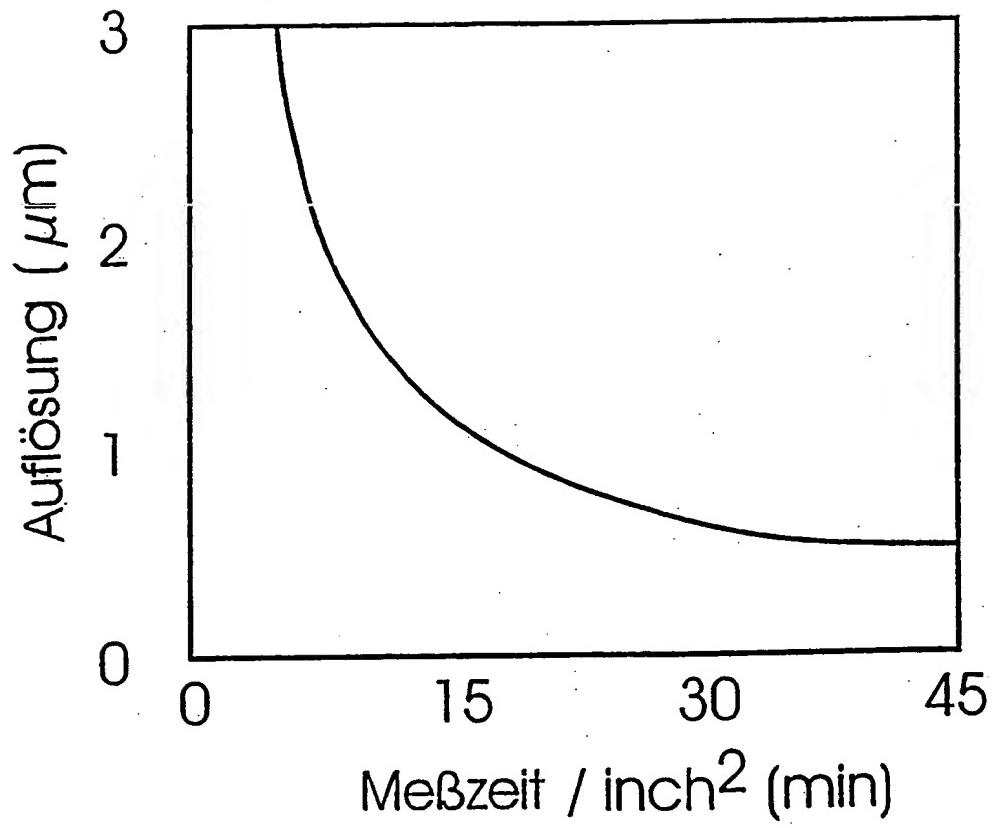


FIG. 7

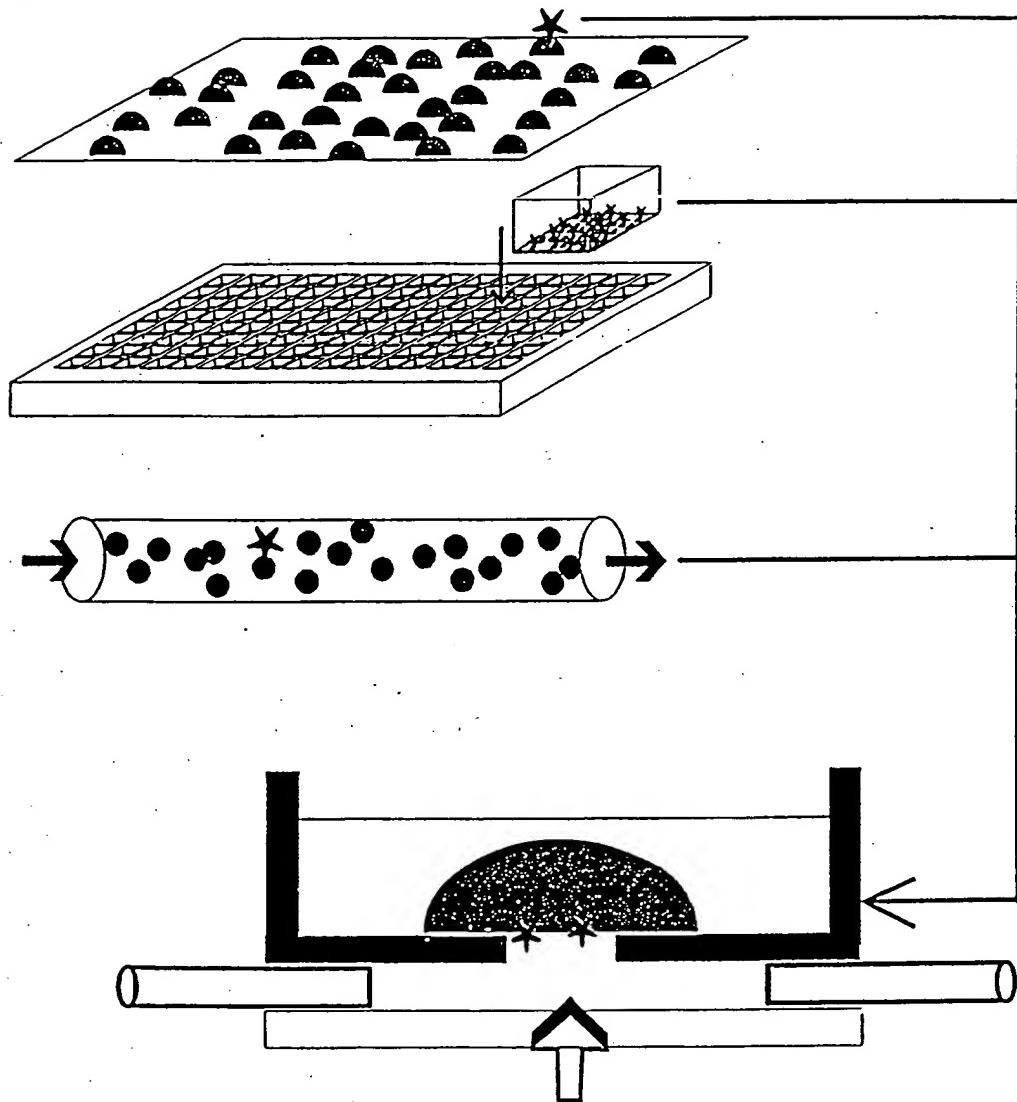


FIG. 8

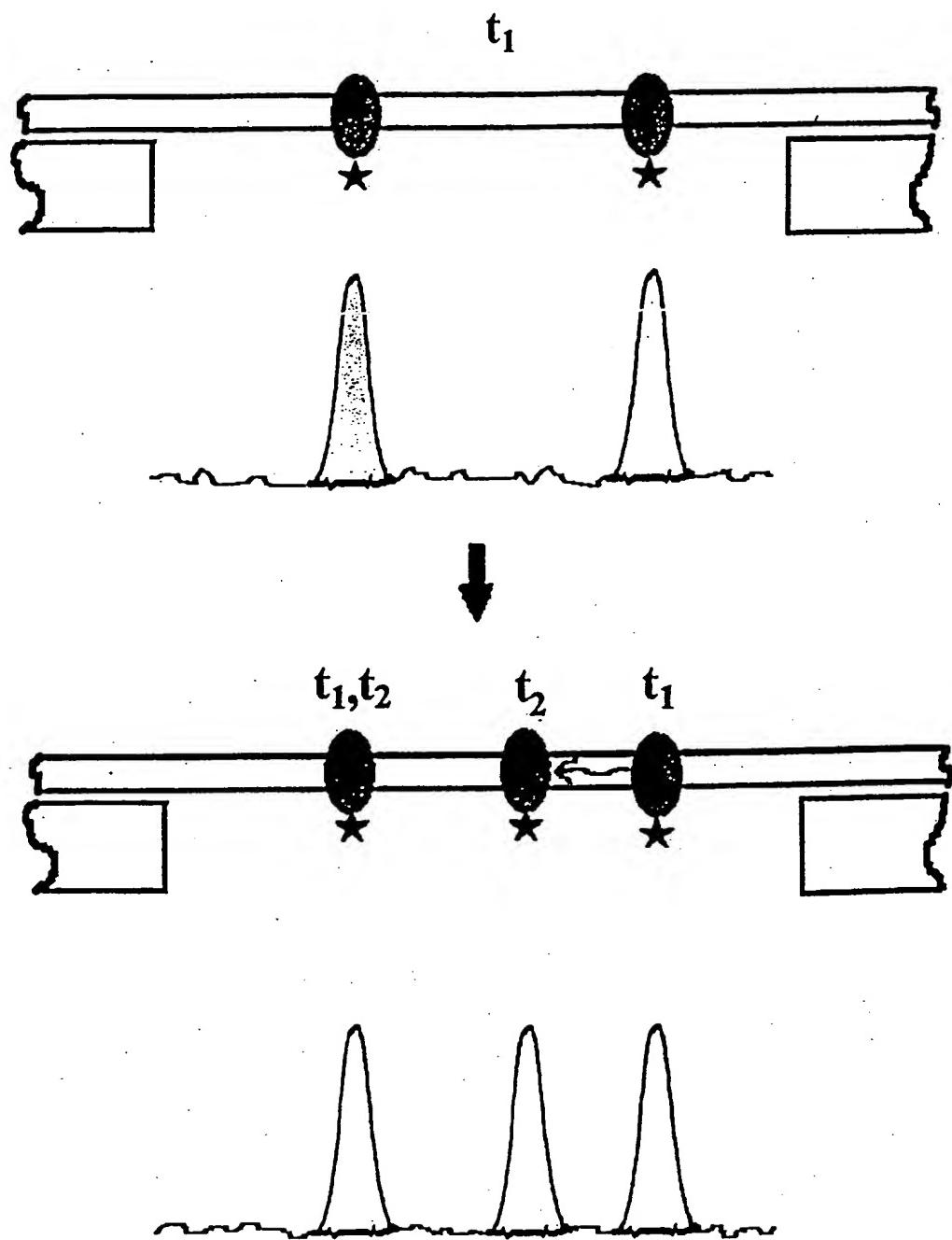


FIG. 9

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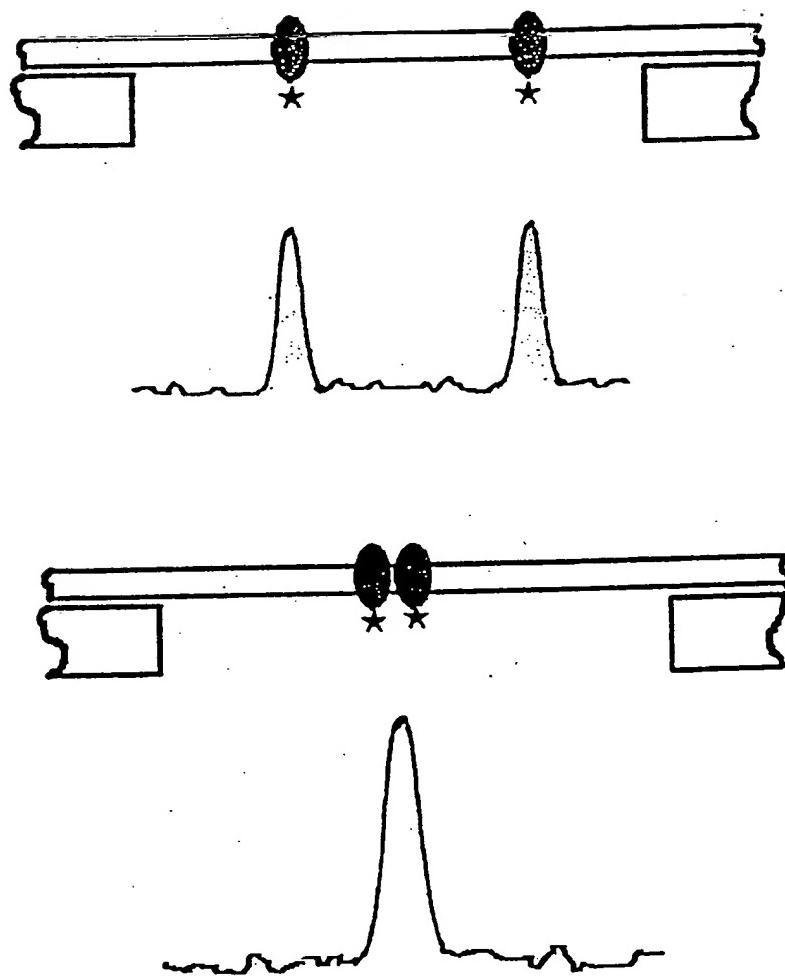


FIG.10

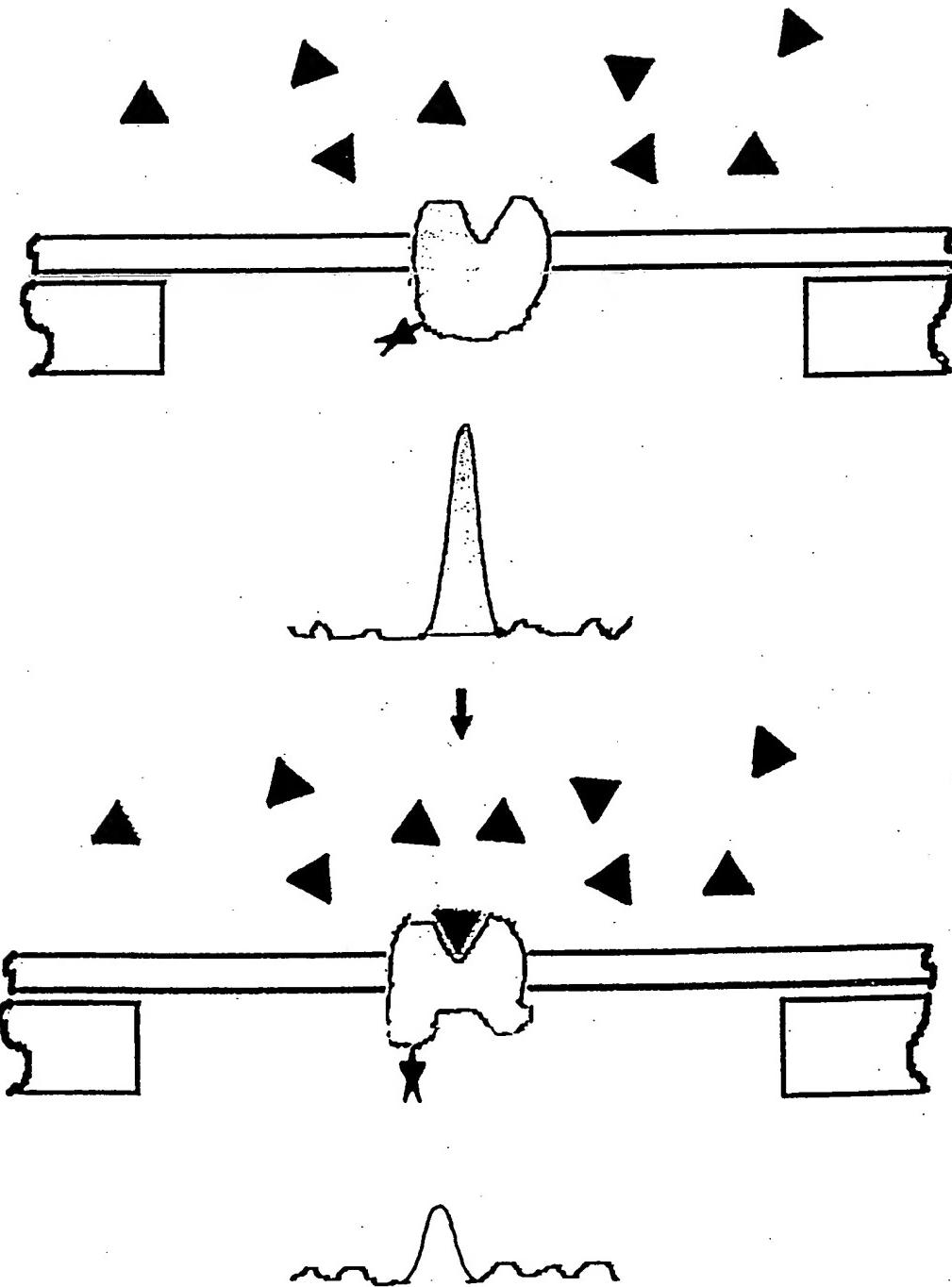


FIG. 11

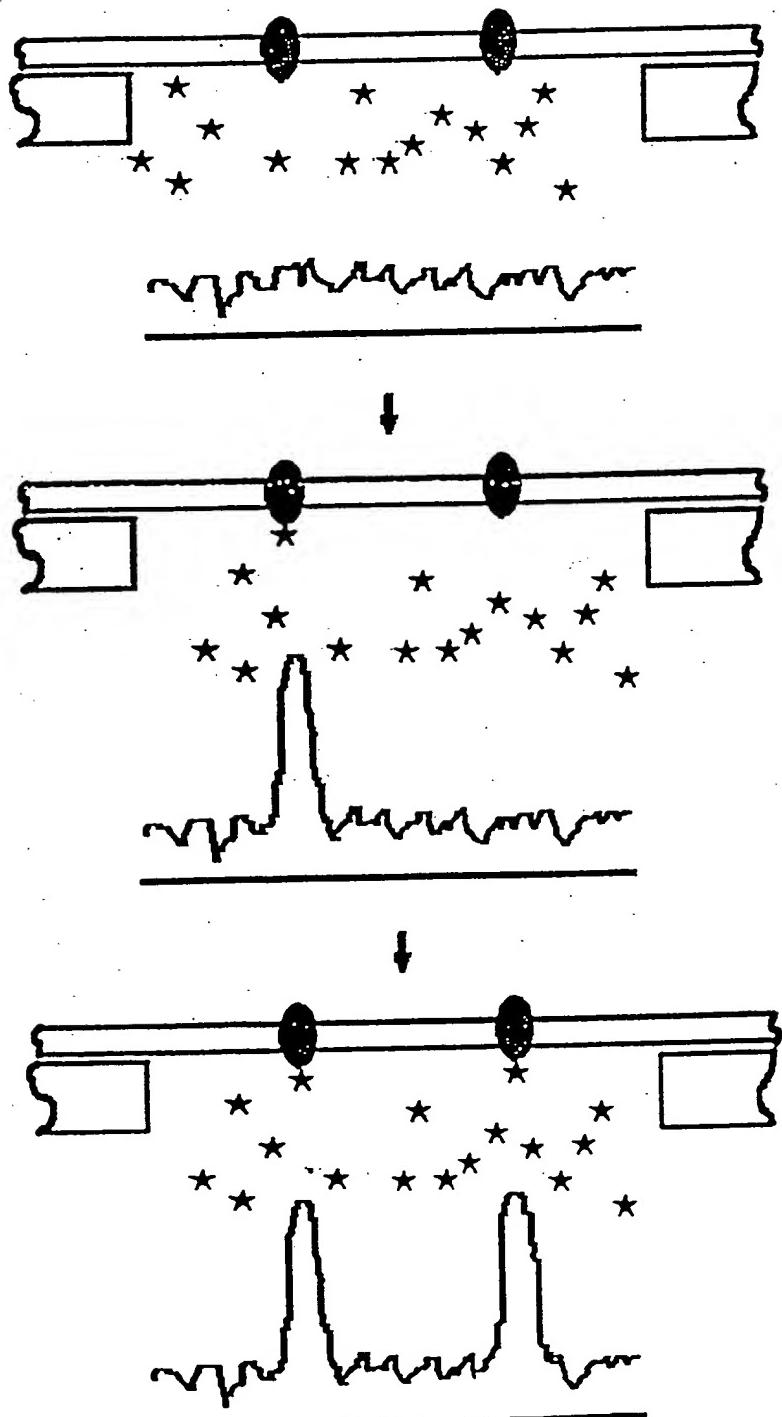


FIG. 12

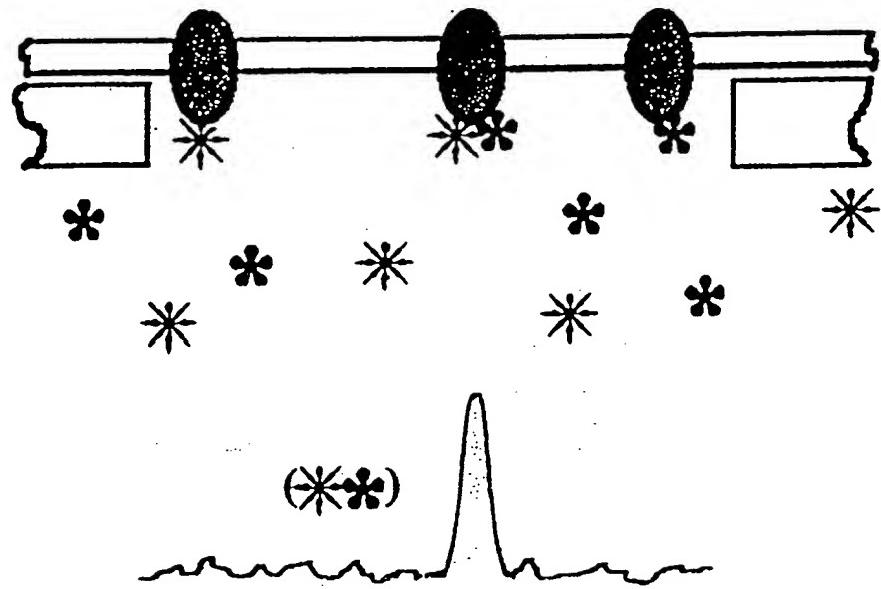


FIG. 13

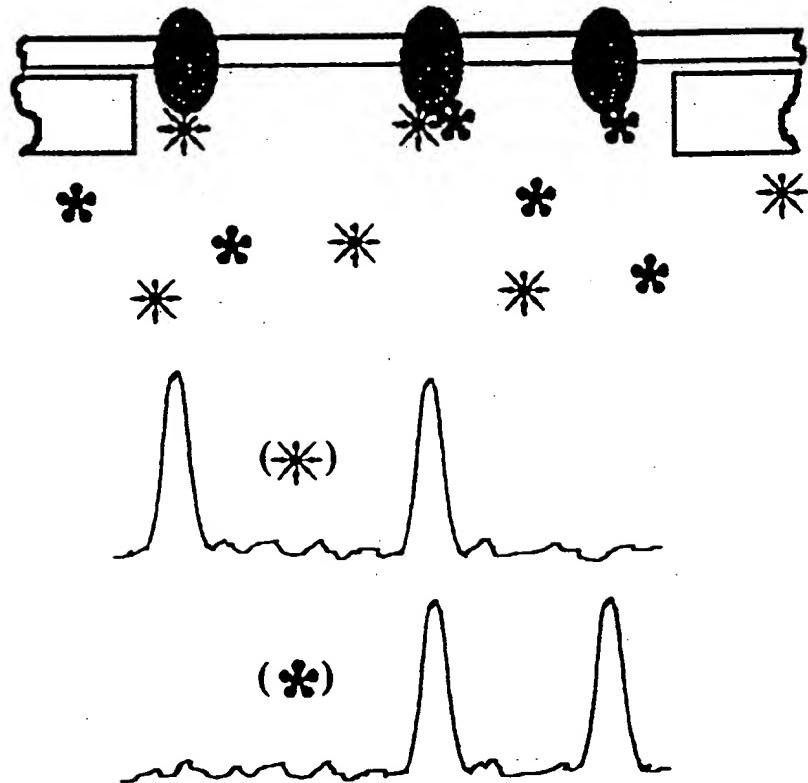


Fig.14

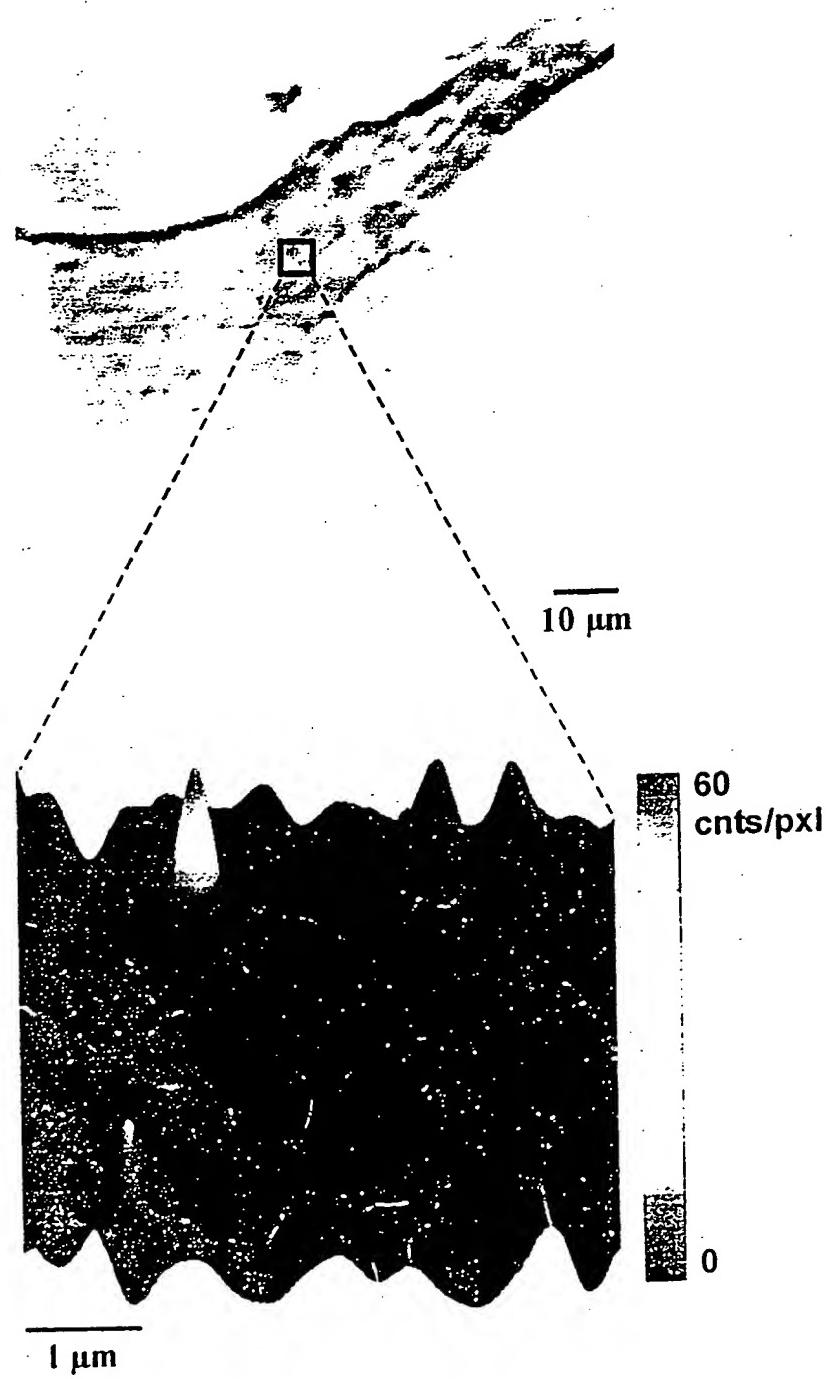


Fig.15

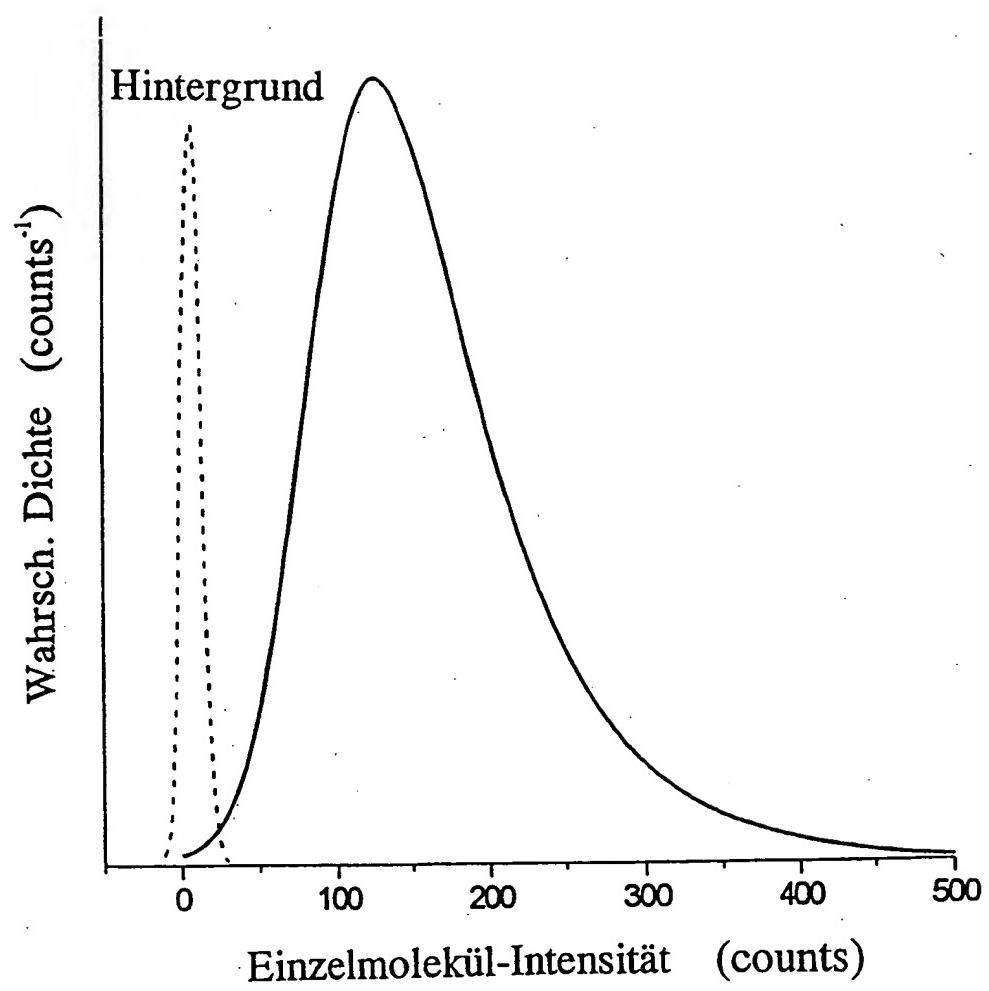


Fig. 16

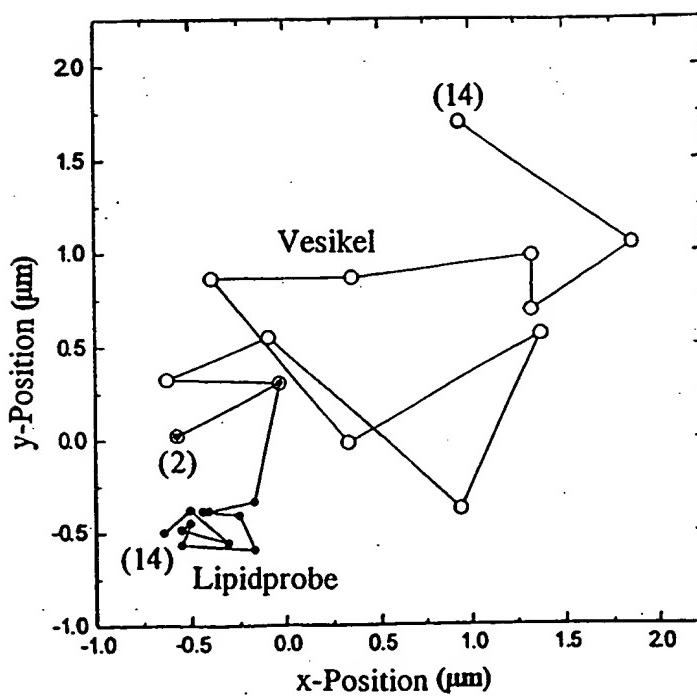
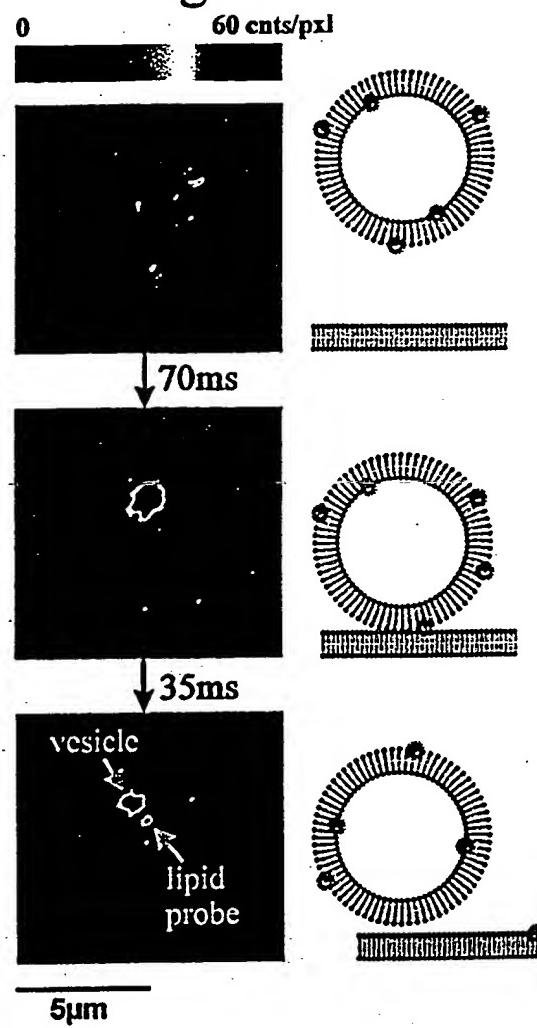


Fig. 17

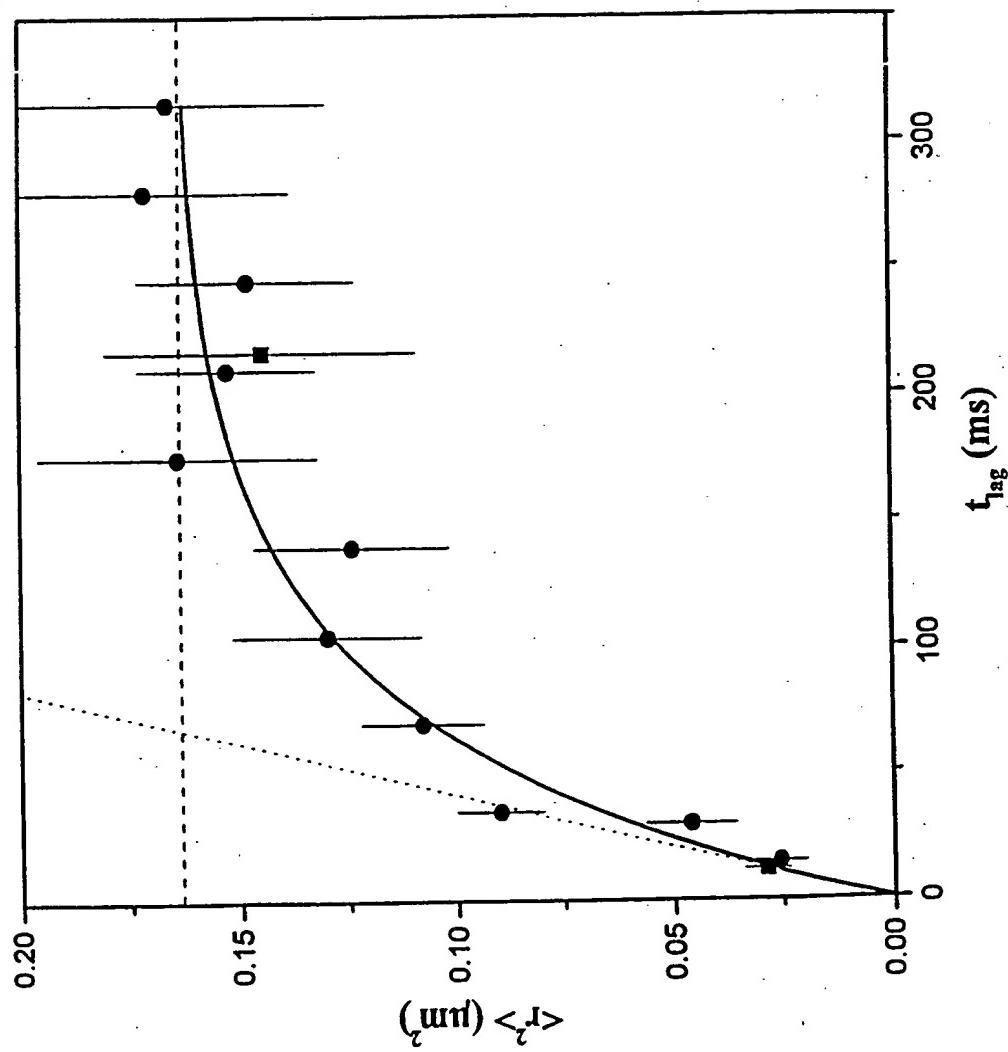
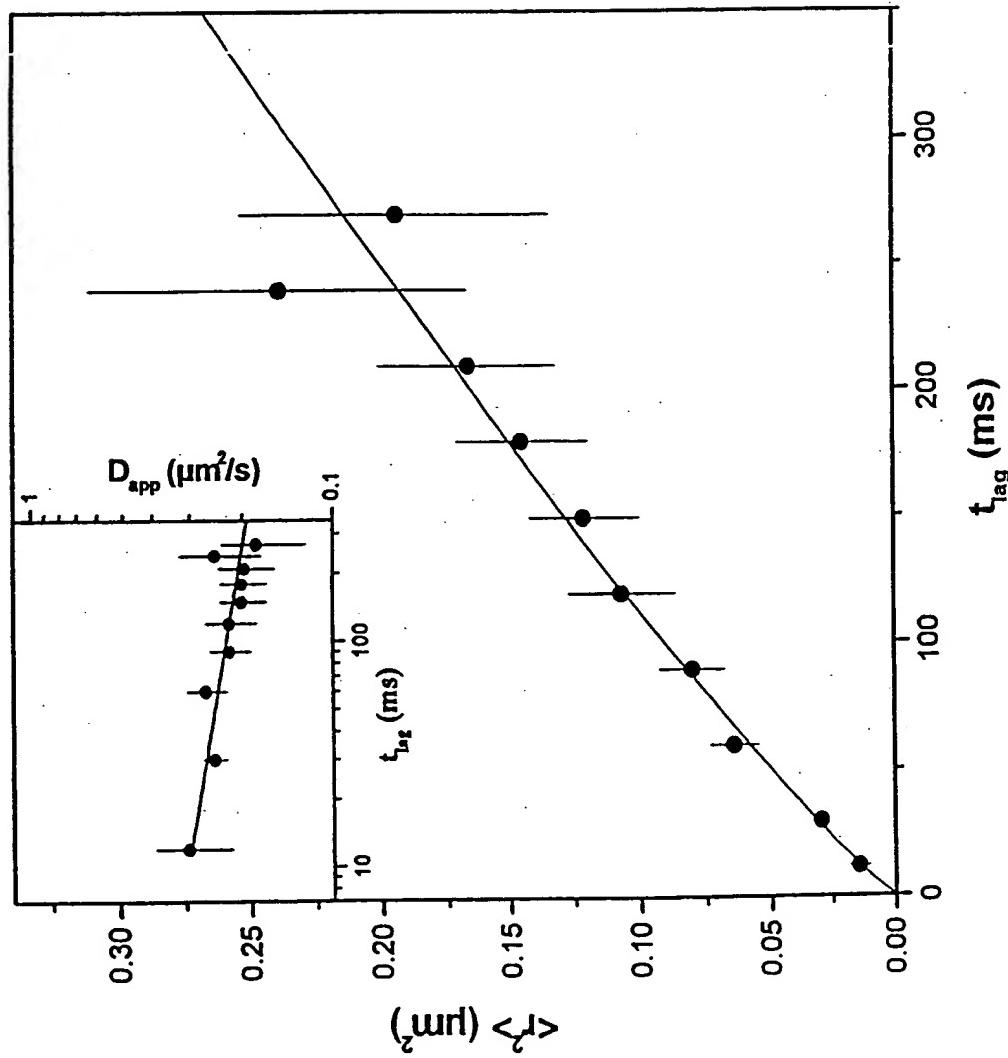
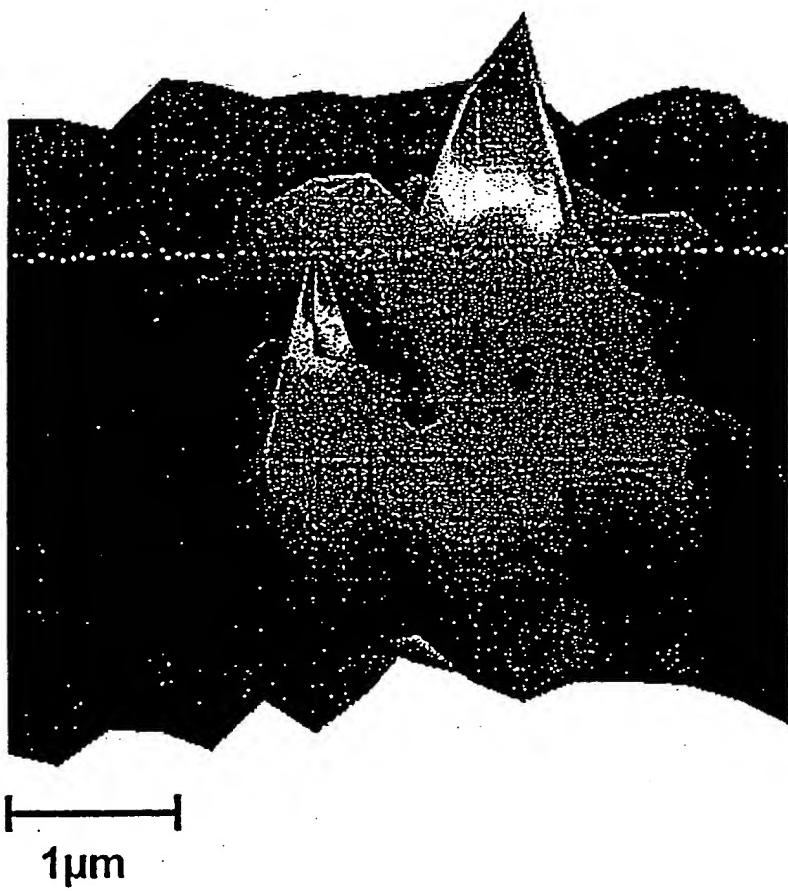


Fig. 18

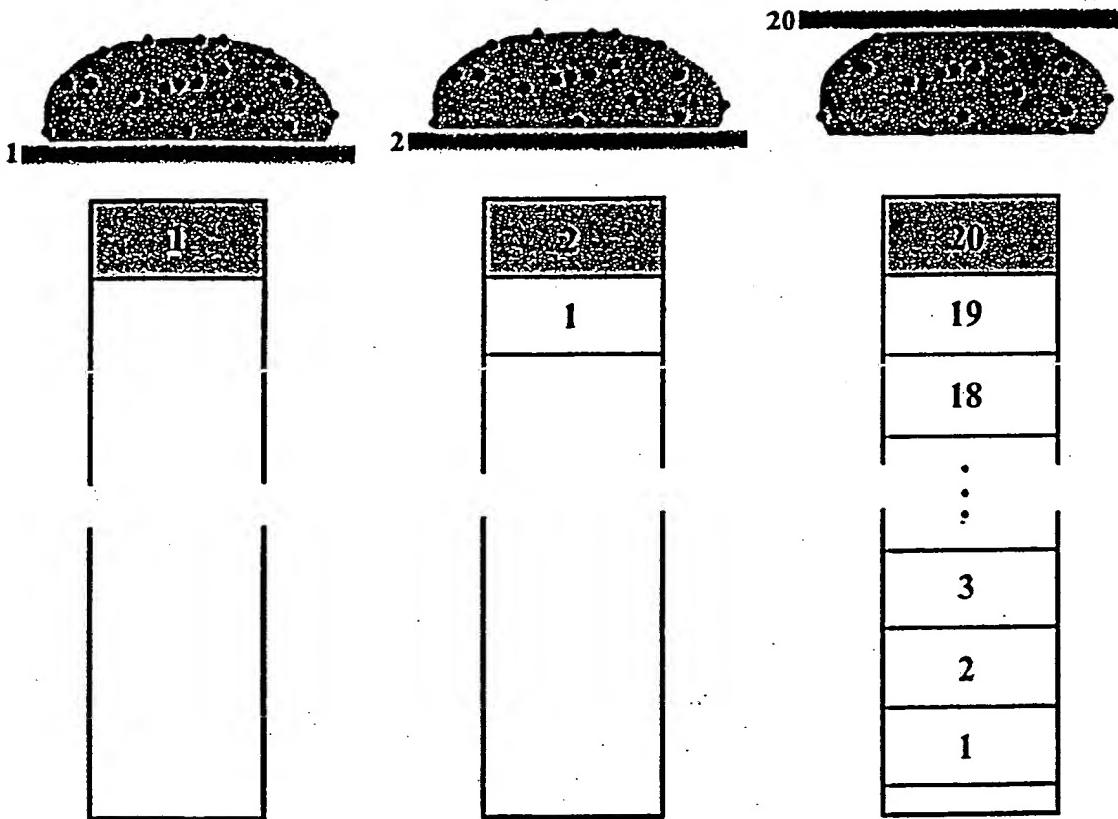


SCANNING ELECTRON MICROGRAPH

FIG. 19

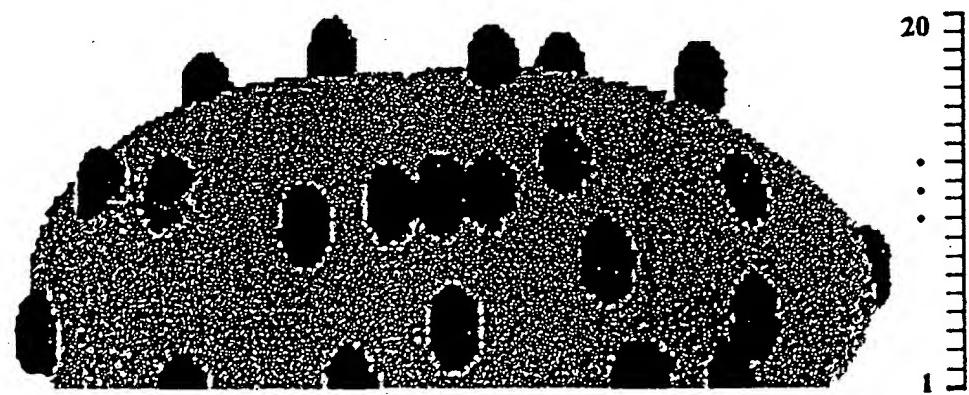


**Fig. 20A**



MESSAGE "TIEGO"

**Fig. 20B**



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FIG. 20C

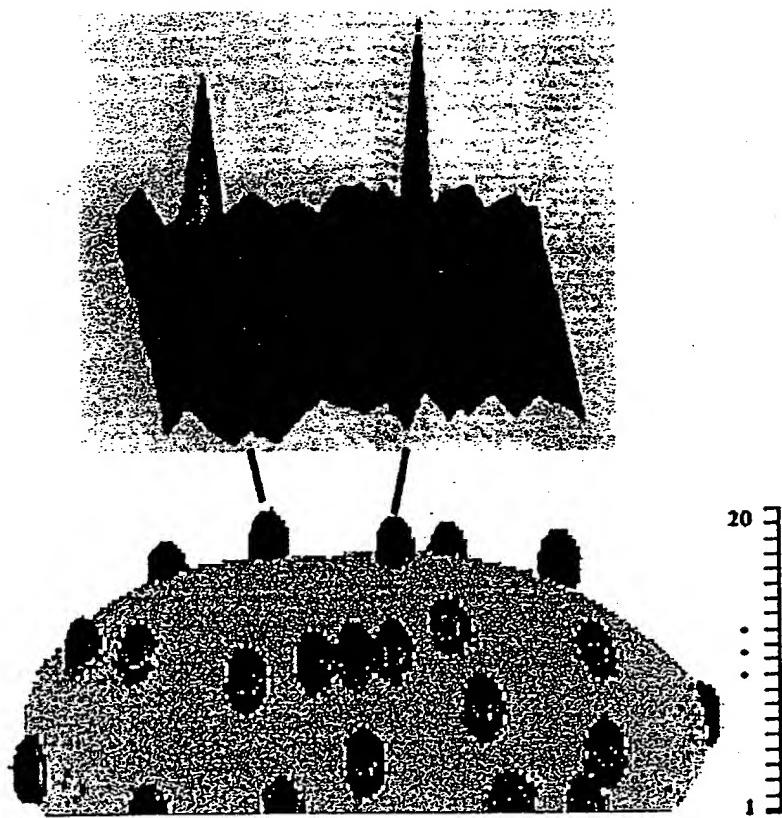


FIG. 21

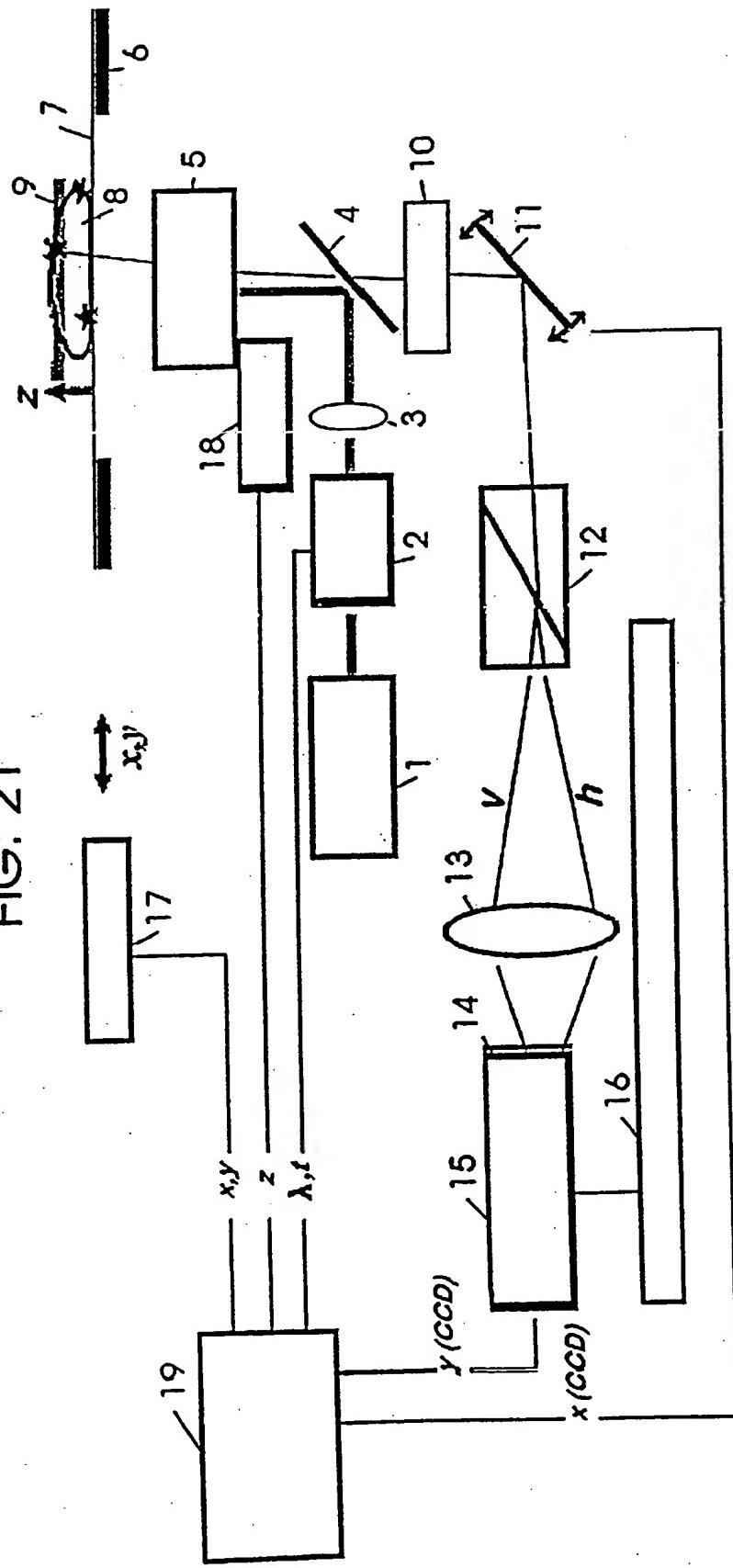


FIG. 22

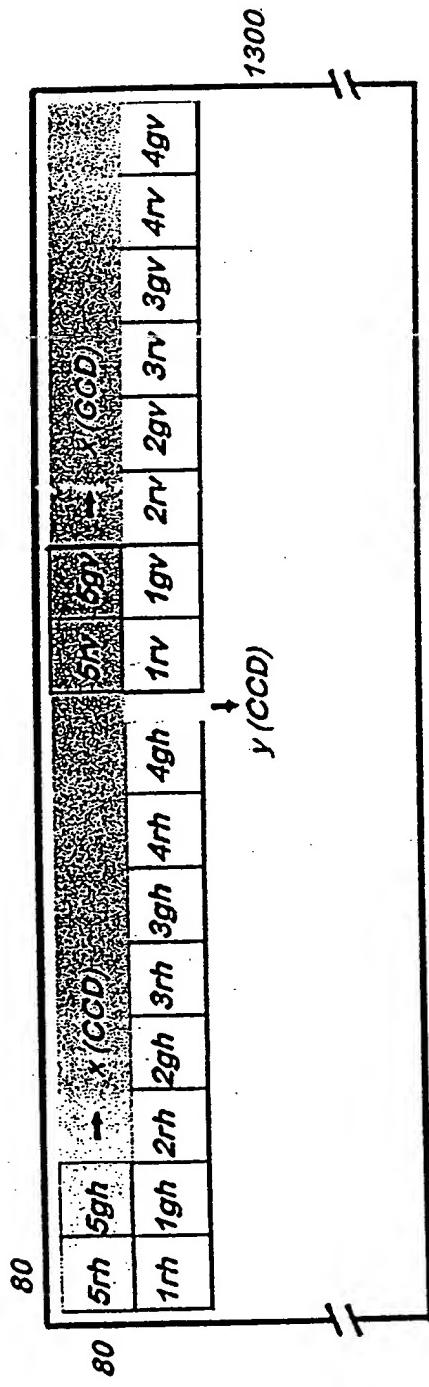


FIG. 23

